



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 10/050,347
Filing Date January 15, 2002
Inventor Gurtej S. Sandhu et al.
Assignee Micron Technology, Inc.
Group Art Unit 2813
Examiner Laura M. Schillinger
Attorney's Docket No. MI22-1897
Title: Methods of Forming Transistors

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

References -- See Attached Form PTO-1449


The attached Form PTO-1449 is submitted in compliance with 37 CFR §1.56. Pursuant to FEDERAL REGISTER, Vol. 69, No. 182, pg. 56542 (September 21, 2004), no copies of any cited U.S. patents or U.S. published applications are included herewith. Copies of all other cited art are attached. No admission is made regarding whether the listed references are prior art.

Respectfully submitted,

Dated: February 22, 2007

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1897		SERIAL NO. 10/050,347	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: Gurtej S. Sandhu			
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U.S. PATENT DOCUMENTS							
*Examiner's Initials	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	AA	6,015,739	1/18/00	Gardner et al.			
	AB	6,057,854	05/2/00	Gardner et al.			
	AC	6,649,58 B1	11/18/03	Cheng et al.			
	AD	2005/0087820 A1	4/28/05	Bai et al.			
	AE	2006/0134864 A1	6/22/06	Higashitani et al.			
	AF						
	AG						
	AH						
	AI						

FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AJ						
	AK						
	AL						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
	AM		
	AN		
	AO		
	AP		
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EXAMINER	DATE CONSIDERED
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